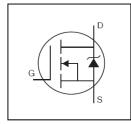
HEXFET® Power MOSFET



Applications

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits



V _{DSS}	100V
R _{DS(on)} typ.	3.7mΩ
R _{DS(on)} max.	4.5mΩ
I _D	72A

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free
- Halogen-Free



G	D	S
Gate	Drain	Source

Page Dort Number	Dookaga Tuna	Standar	d Pack	Orderable Part Number	
Base Part Number	Package Type	Form	Quantity	Orderable Part Number	
IRFI4110GPbF	TO-220 Full-Pak	Tube	50	IRFI4110GPbF	

Absolute Maximum Ratings						
Symbol	Parameter	Max.	Units			
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	72				
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	51	A			
I _{DM}	Pulsed Drain Current ①	290				
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	61	W			
	Linear Derating Factor	0.41	W/°C			
V_{GS}	Gate-to-Source Voltage	± 20	V			
dv/dt	Peak Diode Recovery dv/dt③	27	V/ns			
T_J	Operating Junction and	-55 to + 175				
T _{STG}	Storage Temperature Range		°C			
	Soldering Temperature, for 10 seconds (1.6mm from case)	300				
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)				

Avalanche Characteristics

E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	71	mJ
I _{AR}	Avalanche Current ①	43	Α
E _{AR}	Repetitive Avalanche Energy ①	6.1	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		2.46	°C/W
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount)⑦		65	C/VV

2017-04-27



Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage				V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I _D = 5mA ①
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.7	4.5	mΩ	$V_{GS} = 10V, I_D = 43A$
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
ı	Drain to Course Leakage Current			20		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$
IDSS	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nΛ	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -20V$

Dynamic @ T_J = 25°C (unless otherwise specified)

Dynamic	ynamic @ 1 _J = 25 C (unless otherwise specified)								
gfs	Forward Trans conductance	260			S	$V_{DS} = 50V, I_{D} = 43A$			
Q_g	Total Gate Charge		190	290		I _D = 43A			
Q_{gs}	Gate-to-Source Charge		40		nC	V _{DS} = 50V			
Q_{gd}	Gate-to-Drain Charge		49			V _{GS} = 10V ④			
R_G	Internal Gate Resistance		1.3		Ω				
$t_{d(on)}$	Turn-On Delay Time		24			$V_{DD} = 65V$			
t _r	Rise Time		58		no	I _D = 43A			
$t_{d(off)}$	Turn-Off Delay Time		81		ns	$R_G = 2.6\Omega$			
t _f	Fall Time		71			V _{GS} = 10V ④			
C_{iss}	Input Capacitance		9540			V _{GS} = 0V			
C_{oss}	Output Capacitance		680			V _{DS} = 50V			
C_{rss}	Reverse Transfer Capacitance		300		pF	f = 1.0 MHz			
Coss eff. (ER)	Effective Output Capacitance (Energy Related)		760		•	V _{GS} =0V,V _{DS} = 0V to 80V ⑥			
	Effective Output Capacitance (Time Related)		1120			V _{GS} = 0V, V _{DS} = 0V to 80V ⑤			

Source-Drain	Datings	and Characteristics	
Source-Drain	Raumus	and Characteristics	

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			72		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			290		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 43A, V_{GS} = 0V $ ④
t	Reverse Recovery Time		50	75	ns	$T_J = 25^{\circ}C$
L _{IT}	Treverse recovery Time		60	90	110	$T_J = 125^{\circ}C$
	Daviera Dagaver Chara		100	150		$T_J = 125 ^{\circ}\text{C}$ $V_R = 85V$ $I_F = 43A$
Q _{rr}	Reverse Recovery Charge		140	210	nC	$T_J = 125^{\circ}C$ di/dt= 100A/µs@
I _{RRM}	Reverse Recovery Current		3.5		Α	T _J = 25°C
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- $\, \oplus \,$ Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:local_spin_spin} \mbox{\ensuremath{\Im}} \quad I_{SD} \leq 43A, \ di/dt \leq 1600A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ} C.$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- \circ C_{oss eff.} (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- $^{\circ}$ C_{oss eff.} (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

® R_{θ} is measured at T_{J} approximately 90°C.



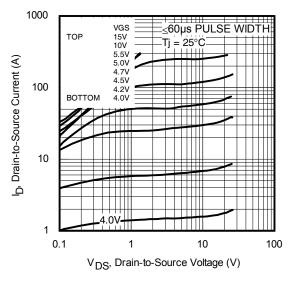


Fig. 1 Typical Output Characteristics

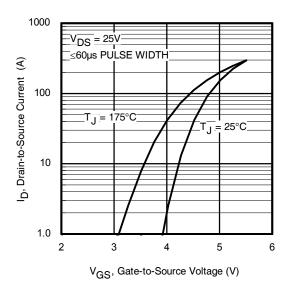


Fig. 3 Typical Transfer Characteristics

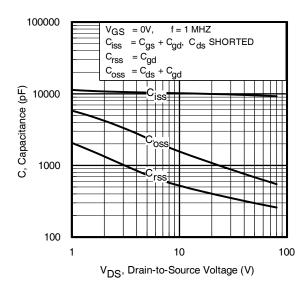


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

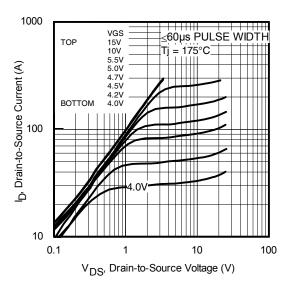


Fig. 2 Typical Output Characteristics

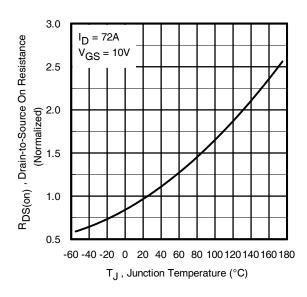


Fig. 4 Normalized On-Resistance vs. Temperature

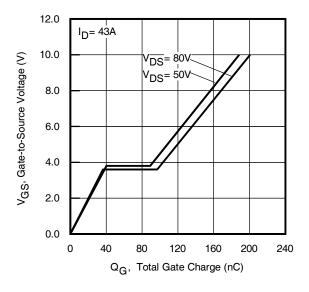


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



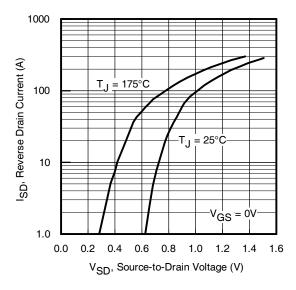


Fig. 7. Typical Source-to-Drain Diode Forward Voltage

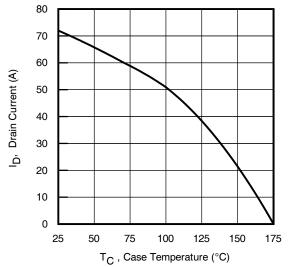


Fig. 9. Maximum Drain Current vs. Case Temperature

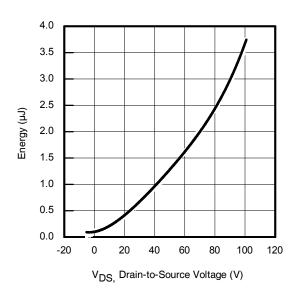


Fig. 11. Typical C_{OSS} Stored Energy

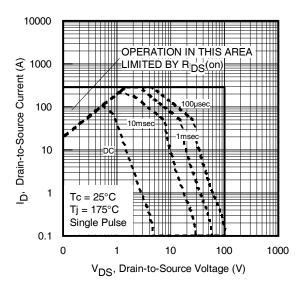


Fig 10. Drain-to-Source Breakdown Voltage

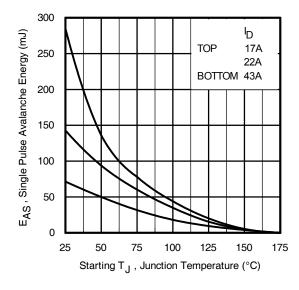


Fig 12. Maximum Avalanche Energy vs. Drain Current

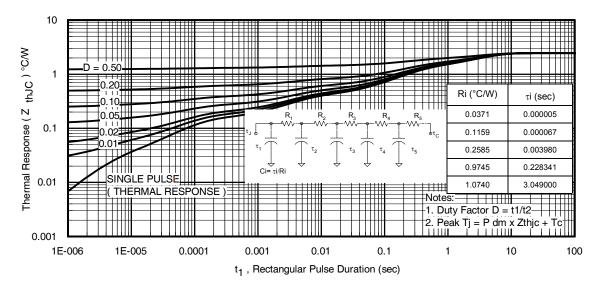


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

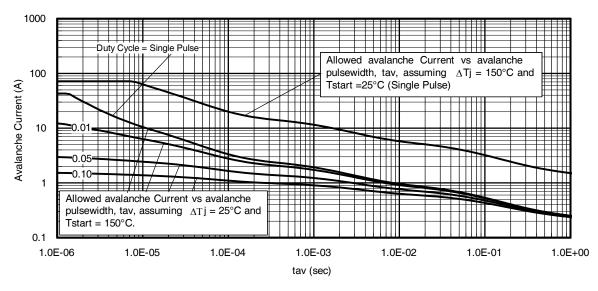
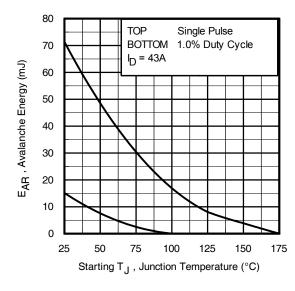


Fig 14. Single Avalanche Event: Pulse Current vs. Pulse Width



 t_{av} = Average time in avalanche.

during avalanche).

1. Avalanche failures assumption:

6. I_{av} = Allowable avalanche current. 7. ΔT = Allowable rise in junction temperature, not to exceed T_{imax} (assumed as 25°C in Figure 14, 15).

4. P_{D (ave)} = Average power dissipation per single avalanche pulse.

temperature far in excess of T_{imax}. This is validated for every part type. 2. Safe operation in Avalanche is allowed as long as T_{imax} is not exceeded.

5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase

3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.

Notes on Repetitive Avalanche Curves, Figures 14, 15:

(For further info, see AN-1005 at www.infineon.com)

Purely a thermal phenomenon and failure occurs at a

D = Duty cycle in avalanche = tav ·f

 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 13) $P_{D (ave)}$ = 1/2 (1.3·BV·I_{av}) = $\Delta T/Z_{thJC}$ $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$ $E_{AS\,(AR)} = P_{D\,(ave)} \cdot t_{av}$

Fig 15. Maximum Avalanche Energy vs. Temperature

2017-04-27



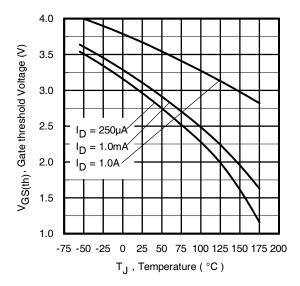


Fig 16. Threshold Voltage vs. Temperature

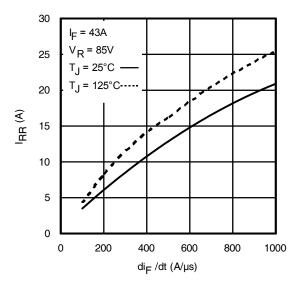


Fig 18. Typical Recovery Current vs. dif/dt

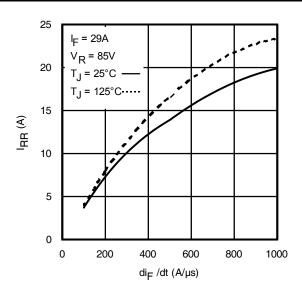


Fig 17. Typical Recovery Current vs. dif/dt

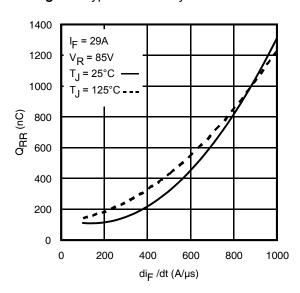


Fig 19. Typical Stored Charge vs. dif/dt

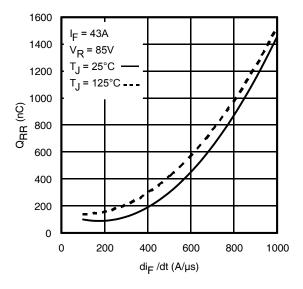
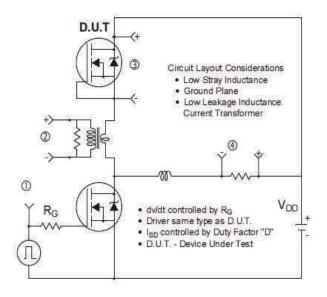


Fig 20. Typical Stored Charge vs. dif/dt





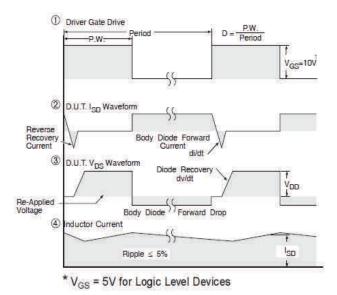


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

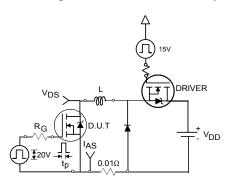


Fig 22a. Unclamped Inductive Test Circuit

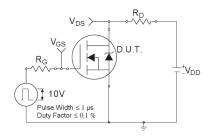


Fig 23a. Switching Time Test Circuit

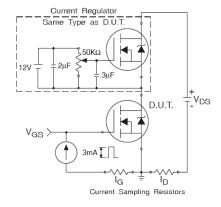


Fig 24a. Gate Charge Test Circuit

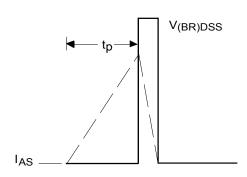


Fig 22b. Unclamped Inductive Waveforms

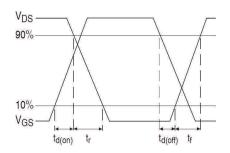


Fig 23b. Switching Time Waveforms

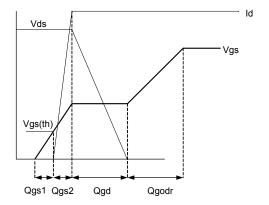
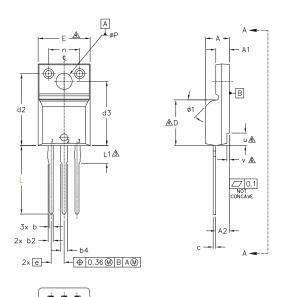
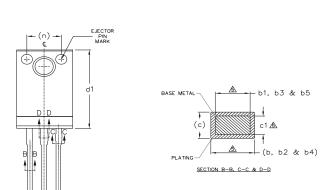


Fig 24b. Gate Charge Waveform



TO-220 Full-Pak Package Outline (Dimensions are shown in millimeters (inches))





- 1.0 DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
- 2,0 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTER MOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63, 65 & c1 APPLY TO BASE METAL ONLY.

 $\sqrt{6.0}$ STEP OPTIONAL ON PLASTIC BODY DEFINED BY DIMENSIONS u & v.

7.0 CONTROLLING DIMENSION: INCHES.

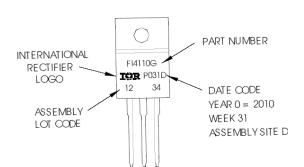
S Y M		DIMEN	SIONS		N	
В	MILLIM	ETERS	INC	HES	0 T E S	
O L	MIN.	MAX.	MIN.	MAX.	S	
Α	4.57	4.83	.180	.190		
A1	2.57	2.82	.101	.111		
A2	2.51	2.92	.099	.115		LEAD ASSIGNMENTS
ь	0.61	0.94	.024	.037		
ь1	0.61	0.89	.024	.035	5	<u>HEXFET</u>
b2	0.76	1.27	.030	.050		1 GATE
b3	0.76	1.22	.030	.048	5	2 DRAIN
b4	1.02	1.52	.040	.060		
b5	1.02	1.47	.040	.058	5	3 SOURCE
С	0.33	0.63	.013	.025		
c1	0.33	0.58	.013	.023	5	
D	8.66	9.80	.341	.386	4	
d1	15.80	16.13	.622	.635		
d2	13.97	14.22	.550	.560		1007 0 0401/
d3	12.29	12.93	.484	.509		<u>IGBTs, CoPACK</u>
E	9.63	10.74	.379	.423	4	1 GATE
е		BSC	.100			2 COLLECTOR
L	13.21	13.72	.520	.540		
L1	3.10	3.68	.122	.145	3	3 EMITTER
n	6.05	6.60	.238	.260		
ØΡ	3.05	3.45	.120	.136		
u	2.39	2.49	.094	.098	6	
V	0.41	0.51	.016	.020	6	
Ø1	_	45°	_	45°		

TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI4110G WITH ASSEMBLY LOT CODE 1234

ASSEMBLED ON WW 31, 2010

Notes: - "P" in assembly line position indicates "Lead-Free" - "G" suffix in part number indicates "Halogen-Free"



TO-220AB Full-Pak packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to website at http://www.irf.com/package/



Qualification Information

Qualification Level	Industrial (per JEDEC JESD47F) [†]	
Moisture Sensitivity Level	TO-220 Full-Pak	N/A
RoHS Compliant	Yes	

† Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comments
04/27/2017	 Changed datasheet with Infineon logo - all pages. Corrected Package Outline on page 8. Corrected fig 19 & 20 –Y axis title from "A" to "nC" on page 6. Added disclaimer on last page.

Trademarks of Infineon Technologies AG

HVIC™, µIPM™, µPFC™, AU-ConvertIR™, AURIX™, C166™, CanPAK™, CIPOS™, CIPURSE™, CoolDP™, CoolGaN™, COOLIR™, CoolMOS™, CoolSET™, CoolSET™, CoolSiC™, DAVE™, DI-POL™, DirectFET™, DrBlade™, EasyPIM™, EconoBRIDGE™, EconoDUAL™, EconoPIM™, EiceDRIVER™, eupec™, FCOS™, GaNpowIR™, HEXFET™, HITFET™, HybridPACK™, iMOTION™, IRAM™, ISOFACE™, IsoPACK™, LEDrivIR™, LITIX™, MIPAQ™, ModSTACK™, my-d™, NovalithIC™, OPTIGA™, OptiMOS™, ORIGA™, PowIRaudio™, PowIRStage™, PrimePACK™, PrimeSTACK™, PROFET™, PRO-SIL™, RASIC™, REAL3™, SmartLEWIS™, SOLID FLASH™, SPOC™, StrongIRFET™, SupIRBuck™, TEMPFET™, TRENCHSTOP™, TriCore™, UHVIC™, XHP™, XMC™

Trademarks updated November 2015

Other Trademarks

All referenced product or service names and trademarks are the property of their respective owners.

Edition 2016-04-19 Published by Infineon Technologies AG 81726 Munich, Germany

© 2016 Infineon Technologies AG. All Rights Reserved.

Do you have a question about this document?

Email: erratum@infineon.com

Document reference ifx1

IMPORTANT NOTICE

The information given in this document shall in no event be regarded as a guarantee of conditions or **characteristics ("Beschaffenheitsgarantie").**

With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

Please note that this product is not qualified according to the AEC Q100 or AEC Q101 documents of the Automotive Electronics Council.

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may not be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.